

Notice of References Cited	Application/Control No. 10/700,225	Applicant(s)/Patent Under Reexamination NIEUWSTADT, MICHEL VAN	
	Examiner Tu M. Nguyen	Art Unit 3748	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-			
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	D	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	X	

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